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Application/Control No.	Applicant(s)/Pater	nt Under	
10/077,367	Reexamination EKKERT, LEONA	.RD	
Examiner	Art Unit		
LIEN TM NGO	3727	Page 1 of 1	•

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-5,972,292	10-1999	DeMeo, Gaetano	422/25
	В	US-6,257,432	07-2001	Ekkert, Len	215/331
	С	US-6,260,722	07-2001	Ekkert, Len	215/331
	D	US-4,196,818	04-1980	Brownbill, Thomas D.	215/252
	E	US-4,089,463	05-1978	Babiol, Pierre	215/329
	F	US-4,106,653	08-1978	Martinelli, Luciano B.	215/256
	G	US-4,450,973 .	05-1984	Toeppen, Thurston	215/329
	Н	US-3,944,104	03-1976	Watson et al.	215/307
	ı	US-5,931,323	08-1999	Wilkinson et al.	215/228
	J	US-6,223,919	05-2001	Kuehn, Hans	215/252
	К	US-3,179,276	04-1965	Safianoff	215/307
	L	US-6,003,699 /	12-1999	Laszlo et al.	215/43
	М	US-3,610,306 /	10-1971	Summers, Kenneth L.	215/270

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	GB 2120219 /	11-1983	GB	Halnes	215/307
	0					
	Р					
	Q					
	R					
	s					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	C	
	٧	
	w	
	х	(C. MDED C 707.05(A))

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.